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Sheet 1 of 1

Form PTO-1449 (Modified)

MAR 18 2002

Atty. Docket No.
74/113

Application No.
10/017,932

INFORMATION DISCLOSURE CITATION
IN AN APPLICATION
(USE SEVERAL SHEETS IF NECESSARY)

Applicant:
Hasman et al

Filing Date:
18 December 2001

Group Art Unit:
2872

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TECHNOLOGY
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EX-2872

U.S. PATENT DOCUMENTS

	EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
AA							
AB							
AC							

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION
							YES
AI							
AJ							

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AM	PA	Bahram Javidi and Takanori Nomura, "Polarization encoding for optical security systems", <i>Optical Engineering</i> vol. 39 no. 9 pp. 2439-2443 (2000),
AN	RA	N. Davidson et al., "Realization of perfect shuffle and inverse perfect shuffle transforms with holographic elements", <i>Applied Optics</i> vol. 31 no. 11 pp. 1810-1812 (1992),
AO	YA	Uwe D. Zeitner et al., "Polarization multiplexing of diffractive elements with metal-stripe grating pixels", <i>Applied Optics</i> vol. 38 no. 11 pp. 2177-2181 (1999)
AP	TA	Gregory P. Nordin et al., "Micropolarizer array for infrared imaging polarimetry", <i>Journal of the Optical Society of America</i> vol. 16 no. 5 pp. 1168-1174 (1999)
	TA	Franco Gori, "Measuring Stokes parameters by means of a polarization grating", <i>Optics Letters</i> vol. 24 no. 9 pp. 584-586 (1999)
	PA	Rigorous Coupled Wave Analysis (RCWA) (M. G. Moharam and T. K. Gaylord, "Rigorous coupled-wave analysis of metallic surface-relief gratings", <i>Journal of the Optical Society of America</i> , part A vol. 3 pp. 1780-1787 (1986).
	PA	Space-Variant polarization state manipulation with computer generated subwavelength metal stripe gratings Bomzon et al <i>Optics Communications</i> 192 (2001) 169-181
	PA	Computer-generated space-variant polarization elements with subwavelength metal stripes, Bomzon et al <i>Optics Letters</i> Jan 2001 vol. 26

EXAMINER

DATE CONSIDERED

8/26/04

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformation and not considered. Include copy of this form with next communication to applicant.